

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination 10/724,671 PARK ET AL.	
		Examiner	Art Unit	Page 1 of 1 Richard Chan

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0119562	06-2003	Kokubo, Takeshi	455/566
*	B	US-2001/0016508	08-2001	Kido et al.	455/575
*	C	US-2006/0035680	02-2006	Kokubo, Takeshi	455/566
*	D	US-2006/0019728	01-2006	Sakamoto et al.	455/575.3
*	E	US-2005/0192066	09-2005	Park et al.	455/575.3
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages
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	V	
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	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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